ESE680-002 (ESE534): Computer Organization

Day 25: April 16, 2007
Defect and Fault Tolerance

Today

- Defect and Fault Tolerance
  - Problem
  - Defect Tolerance
  - Fault Tolerance

Warmup Discussion

- Where do we guard against defects and faults today?

Motivation: Probabilities

- Given:
  - N objects
  - P yield probability
- What's the probability for yield of composite system of N items?
  - Asssume iid faults
  - P(N items good) = P^N

Probabilities

- P(N items good) = P^N
- $N=10^6$, P=0.999999
- P(all good) ~= 0.37
- $N=10^7$, P=0.999999
- P(all good) ~= 0.000045

Simple Implications

- As N gets large
  - must either increase reliability
  - …or start tolerating failures
- N
  - memory bits
  - disk sectors
  - wires
  - transmitted data bits
  - processors
  - transistors
  - molecules
  - As devices get smaller, failure rates increase
  - chemists think P=0.95 is good
  - As devices get faster, failure rate increases

Defining Problems

Three "problems"

- Manufacturing imperfection
  - Shorts, breaks
  - wire/node X shorted to power, ground, another node
  - Doping/resistance variation too high
- Parameters vary over time
  - Electromigration
  - Resistance increases
- Incorrect operation
  - node X value flips
    - crosstalk
    - alpha particle
    - bad timing

Defects

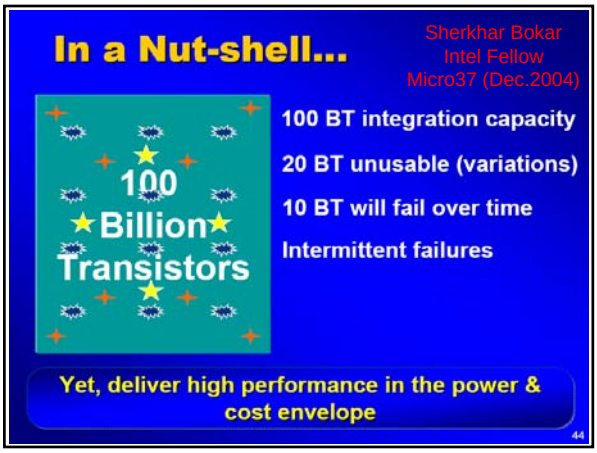
- Shorts example of defect
- Persistent problem
  - reliably manifests
- Occurs before computation
- Can test for at fabrication / boot time and then avoid
- (1^{st} half of lecture)

Faults

- Alpha particle bit flips is an example of a fault
- Fault occurs dynamically during execution
- At any point in time, can fail
  - (produce the wrong result)
- (2^{nd} half of lecture)

Lifetime Variation

- Starts out fine
- Over time changes
  - *E.g.* resistance increases until out of spec.
- Persistent
  - So can use defect techniques to avoid
- But, onset is dynamic
  - Must use fault detection techniques to recognize?



Defect Rate

- Device with 10^{11} elements (100BT)
- 3 year lifetime = 10^8 seconds
- Accumulating up to 10% defects
- 10^{10} defects in 10^8 seconds
  - →1 new defect every 10ms
- At 10GHz operation:
  - One new defect every 10^8 cycles
  - $P_{newdefect}=10^{-19}$

First Step to Recover

Admit you have a problem

(observe that there is a failure)

Detection

- Determine if something wrong?
  - – Some things easy
    - ….won't start
  - – Others tricky
    - …one **and** gate computes False & True→True
- Observability
  - – can see effect of problem
  - – some way of telling if defect/fault present

Detection

- Coding
  - – space of legal values << space of all values
  - – should only see legal
  - – *e.g.* parity, ECC (Error Correcting Codes)
- Explicit test (defects, recurring faults)
  - – ATPG = Automatic Test Pattern Generation
  - – Signature/BIST=Built-In Self-Test
  - – POST = Power On Self-Test
- Direct/special access
  - – test ports, scan paths

Coping with defects/faults?

- **Key idea:** redundancy
- Detection:
  - – Use redundancy to detect error
- Mitigating: use redundant hardware
  - – Use spare elements in place of faulty elements (defects)
  - – Compute multiple times so can discard faulty result (faults)
  - – Exploit Law-of-Large Numbers

Defect Tolerance

Two Models

- Disk Drives (defect map)
- Memory Chips (perfect chip)

Disk Drives

- Expose defects to software
  - software model expects faults
    - Create table of good (bad) sectors
  - manages by masking out in software
    - (at the OS level)
    - Never allocate a bad sector to a task or file
  - yielded capacity varies

Memory Chips

- Provide model in **hardware** of perfect chip
- Model of perfect memory at capacity X
- Use redundancy in hardware to provide perfect model
- Yielded capacity fixed
  - discard part if not achieve

Example: Memory

- Correct memory:
  - N slots
  - each slot reliably stores last value written
- Millions, billions, etc. of bits…
  - have to get them all right?

Memory Defect Tolerance

- Idea:
  - few bits may fail
  - provide more raw bits
  - configure so yield what looks like a perfect memory of specified size

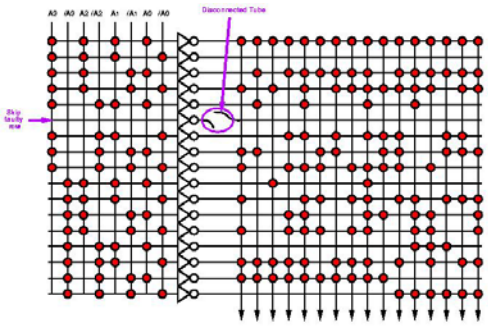
Memory Techniques

- Row Redundancy
- Column Redundancy
- Block Redundancy

Row Redundancy

- Provide extra rows
- Mask faults by avoiding bad rows
- Trick:
  - have address decoder substitute spare rows in for faulty rows
  - use fuses to program

Spare Row

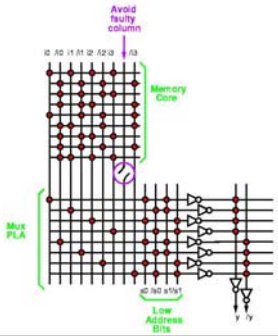


Column Redundancy

- Provide extra columns
- Program decoder/mux to use subset of columns

Spare Memory Column

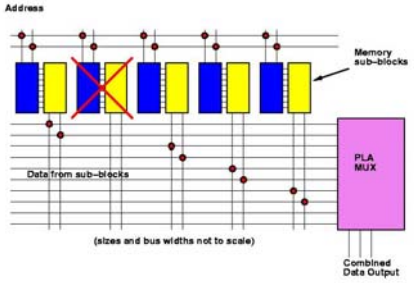
- Provide extra columns
- Program output mux to avoid



Block Redundancy

- Substitute out entire block
  - *e.g.* memory subarray
    - include 5 blocks
      - only need 4 to yield perfect
    - (N+1 sparing more typical for larger N)

Spare Block



Yield M of N

- P(M of N) = P(yield N)
  + (N choose N-1) P(exactly N-1)
  + (N choose N-2) P(exactly N-2)…
  + (N choose N-M) P(exactly N-M)…
  [think binomial coefficients]

M of 5 example

- $1*P^5 + 5*P^4(1-P)^1+10P^3(1-P)^2+10P^2(1-P)^3+5P^1(1-P)^4 + 1*(1-P)^5$
- Consider P=0.9
  - $1*P^5$ 0.59 M=5 P(sys)=0.59
  - $5*P^4(1-P)^1$ 0.33 M=4 P(sys)=0.92
  - $10P^3(1-P)^2$ 0.07 M=3 P(sys)=0.99
  - $10P^2(1-P)^3$ 0.008
  - $5P^1(1-P)^4$ 0.00045
  - $1*(1-P)^5$ 0.00001

Can achieve higher system yield than individual components!

Repairable Area

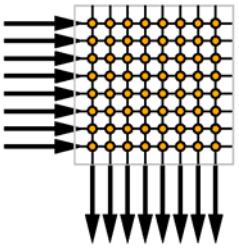
- Not all area in a RAM is repairable
  - memory bits spare-able
  - io, power, ground, control not redundant

Repairable Area

- P(yield) = P(non-repair) * P(repair)
- $P(\text{non-repair}) = P^N$
  - N<<Ntotal
  - Maybe P > Prepair
    - e.g. use coarser feature size
- P(repair) ~ P(yield M of N)

Consider a Crossbar

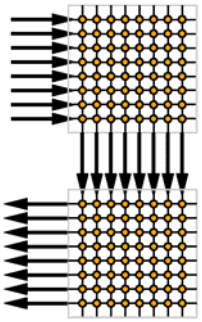
- Allows me to connect any of N things to each other
  - E.g.
    - N processors
    - N memories
    - N/2 processors
    + N/2 memories



Crossbar Buses and Defects

- Two crossbars
- Wires may fail
- Switches may fail

- Provide more wires
  - Any wire fault avoidable
    - M choose N



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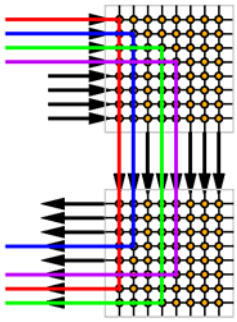

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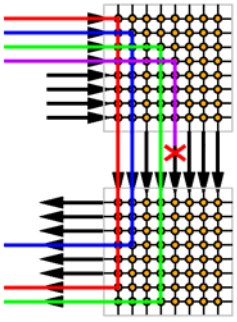
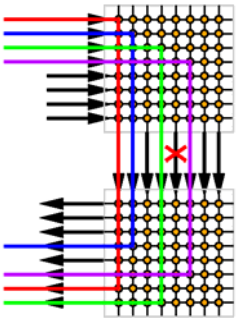


Crossbar Buses and Faults

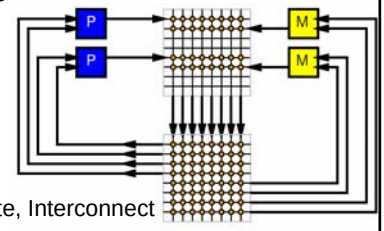
- Two crossbars
- Wires may fail
- Switches may fail

- Provide more wires
  - Any wire fault avoidable
    - M choose N
  - Same idea



Simple System

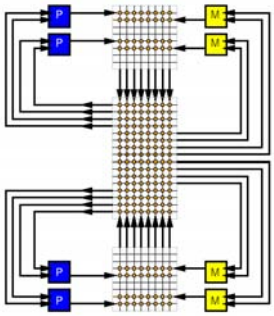
- P Processors
- M Memories
- Wires



Memory, Compute, Interconnect

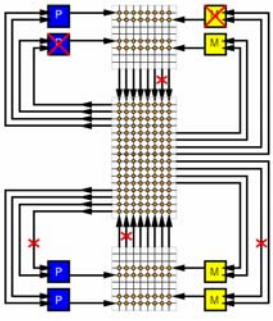
Simple System w/ Spares

- P Processors
- M Memories
- Wires
- Provide spare
  - Processors
  - Memories
  - Wires



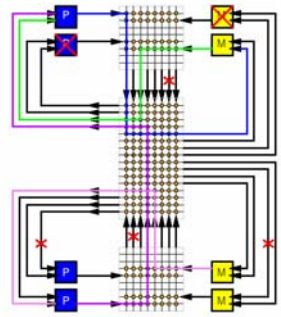
Simple System w/ Defects

- P Processors
- M Memories
- Wires
- Provide spare
  - Processors
  - Memories
  - Wires
- ...and defects



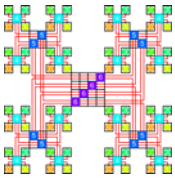
Simple System Repaired

- P Processors
- M Memories
- Wires
- Provide spare
  - Processors
  - Memories
  - Wires
- Use crossbar to switch together good processor and memories



In Practice

- Crossbars are inefficient [Day13]
- Use switching networks with
  - Locality
  - Segmentation
- …but basic idea for sparing is the same



Fault Tolerance

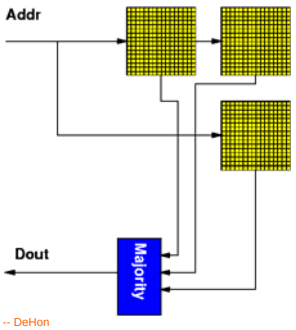
Faults

- Bits, processors, wires
  - May fail during operation
- Basic Idea same:
  - Detect failure using redundancy
  - Correct
- Now
  - Must identify and correct online with the computation

Simple Memory Example

- **Problem:** bits may lose/change value
  - Alpha particle
  - Molecule spontaneously switches
- **Idea:**
  - Store multiple copies
  - Perform majority vote on result

Redundant Memory



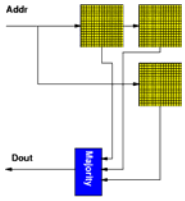
Redundant Memory

- Like M-choose-N
- Only fail if >(N-1)/2 faults
- P=0.9
- P(2 of 3)

  All good: $(0.9)^3 = 0.729$

  + Any 2 good: $3(0.9)^2(0.1)=0.243$

  $= 0.971$

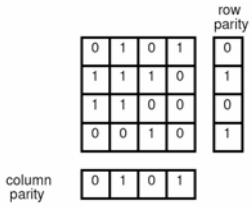


Better: Less Overhead

- Don't have to keep N copies
- Block data into groups
- Add a small number of bits to detect/correct errors

Row/Column Parity

- Think of NxN bit block as array
- Compute row and column parities
  - (total of 2N bits)



Row/Column Parity

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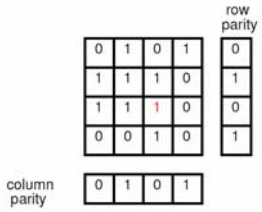
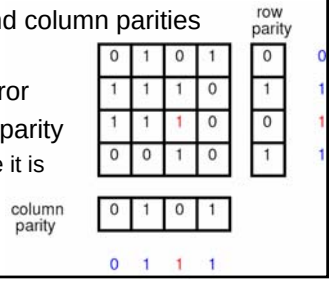


Row/Column Parity

- Think of NxN bit block as array
- Compute row and column parities
  - (total of 2N bits)
- Any single bit error
- By recomputing parity
  - Know which one it is
  - Can correct it



In Use Today

- Conventional DRAM Memory systems
  - Use 72b ECC (Error Correcting Code)
  - On 64b words
  - Correct any single bit error
  - Detect multibit errors
- CD blocks are ECC coded
  - Correct errors in storage/reading

Interconnect

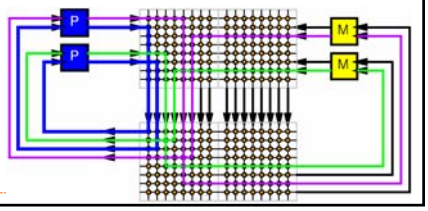
- Also uses checksums/ECC
  - Guard against data transmission errors
  - Environmental noise, crosstalk, trouble sampling data at high rates…
- Often just detect error
- Recover by requesting retransmission
  - *E.g.* TCP/IP (Internet Protocols)

Interconnect

- Also guards against whole path failure
- Sender expects acknowledgement
- If no acknowledgement will retransmit
- If have multiple paths
  - …and select well among them
  - Can route around any fault in interconnect

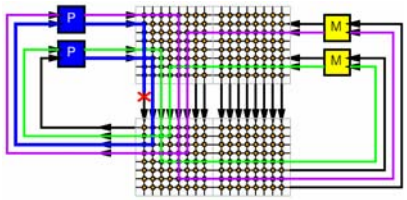
Interconnect Fault Example

- Send message
- Expect Acknowledgement



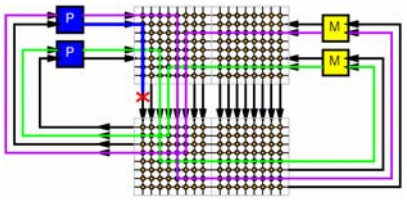
Interconnect Fault Example

- Send message
- Expect Acknowledgement
- If Fail



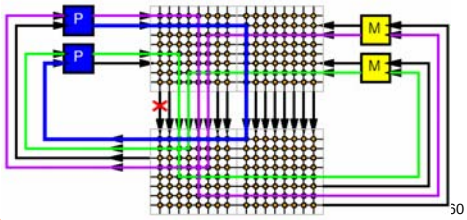
Interconnect Fault Example

- Send message
- Expect Acknowledgement
- If Fail
  - No ack



Interconnect Fault Example

- If Fail → no ack
  - Retry
  - Preferably with different resource



Interconnect Fault Example

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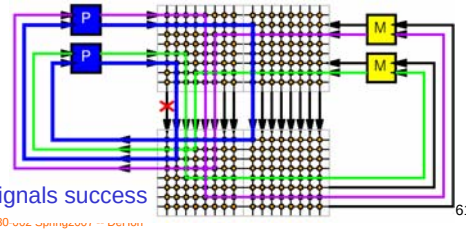
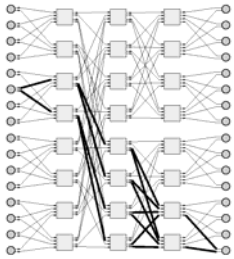


Ack signals success

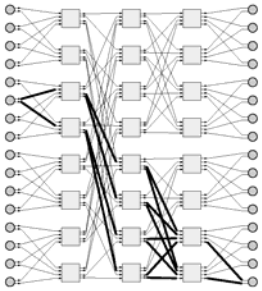
Transit Multipath

- Butterfly (or Fat-Tree) networks with multiple paths



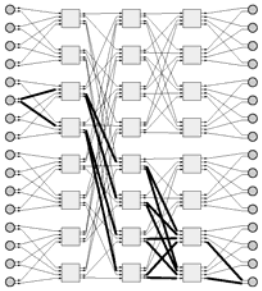
Multiple Paths

- Provide bandwidth
- Minimize congestion
- Provide **redundancy** to tolerate faults

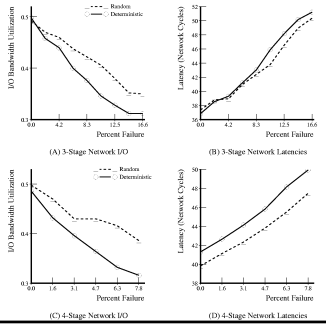


Routers May be faulty (links may be faulty)

- Dynamic
  - Corrupt data
  - Misroute
  - Send data nowhere

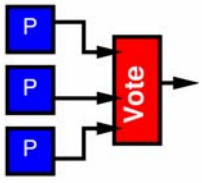


Multibutterfly Performance w/ Faults



Compute Elements

- Simplest thing we can do:
  - Compute redundantly
  - Vote on answer
  - Similar to redundant memory



Compute Elements

- Unlike Memory
  - State of computation important
  - Once a processor makes an error
    - All subsequent results may be wrong
- Response
  - "reset" processors which fail vote
  - Go to spare set to replace failing processor

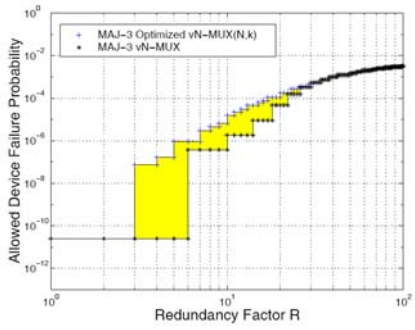
In Use

- NASA Space Shuttle
  - Uses set of 4 voting processors
- Boeing 777
  - Uses voting processors
    - (different architectures, code)

Forward Recovery

- Can take this voting idea to gate level
  - VonNeuman 1956
- Basic gate is a majority gate
  - Example 3-input voter
- Alternate stages
  - Compute
  - Voting (restoration)
- Number of technical details…
- High level bit:
  - Requires Pgate>0.996
  - Can make whole system as reliable as individual gate

Majority Multiplexing



Maybe there's a better way…

[Roy+Beiu/IEEE Nano2004]

Rollback Recovery

- Commit state of computation at key points
  - to memory (ECC, RAID protected...)
  - …reduce to previously solved problem…
- On faults (lifetime defects)
  - recover state from last checkpoint
  - like going to last backup….
  - …(snapshot)

Defect vs. Fault Tolerance

- Defect
  - Can tolerate large defect rates (10%)
    - Use virtually all good components
    - Small overhead beyond faulty components
- Fault
  - Require lower fault rate (*e.g.* VN <0.4%)
    - Overhead to do so can be quite large

Summary

- Possible to engineer practical, reliable systems from
  - Imperfect fabrication processes (defects)
  - Unreliable elements (faults)
- We do it today for large scale systems
  - Memories (DRAMs, Hard Disks, CDs)
  - Internet
- …and critical systems
  - Space ships, Airplanes
- Engineering Questions
  - Where invest area/effort?
    - Higher yielding components? Tolerating faulty components?
  - Where do we invoke law of large numbers?
    - Above/below the device level

Admin

- Final Class on Wednesday
  - Will have course feedback forms
- André traveling 18—26th
  - Won't find in office
- Final exercise
  - Due Friday May 4th
  - Proposals for Problem 3 before Friday April 27th
    - …same goes for clarifying questions

Big Ideas

- Left to itself:
  - reliability of system << reliability of parts
- Can design
  - system reliability >> reliability of parts [defects]
  - system reliability ~= reliability of parts [faults]
- For large systems
  - must engineer reliability of system
  - …all systems becoming "large"

Big Ideas

- Detect failures
  - static: directed test
  - dynamic: use **redundancy** to guard
- Repair with **Redundancy**
- Model
  - establish and provide model of correctness
    - Perfect component model (memory model)
    - Defect map model (disk drive model)